

IEEE Berkshire Section
Annual High School STEM Research Challenge – 2024

This section covers the “rules” of the 2024 contest.

- This contest is limited to students from Berkshire County.
- Two prize divisions will be established; grades 9-10 and grades 11-12.
- To submit the paper the student must e-mail the paper to BerkshireSection@ieee.org.
- The student must submit the entries in document form (please no PDFs) via email no later than 11:59PM on Monday, March 4, 2024. If there are any problems with submission please e-mail.
- The cover sheet will be detached prior to judging to remove the identity of the author and the school. Each paper will be assigned a code. No identification of the author, school, or school personnel may be included in the text or references, including the web search records.
- Repeat the paper’s title on the top of the first page of text. Paginate the text pages (e.g., 1/5, 2/5 ...). Omit numbering on the title Page.
- Papers should total approximately 500 to 1,500 words max of 12-point double-spaced type (about three to five single sided pages). Word/page count does NOT include the space used for formulas, drawings, charts, graphs or bibliography. Excessive length reduces the chances of winning.
- A bibliography of the sources must be included, or the paper will be eliminated from the competition. Citations for the sources must be noted within the text. APA, MLA or the citation format used at the submitting school are acceptable. Note the date on which the database sources were accessed.
- Entries will be judged on the choice and appropriateness of the topic, the scientific content, the student's comprehension and personal reflections on material, the accuracy of the analysis; and the quality of the writing, including the documentation of the references. (Please refer to the "substance" section of rules.)
- The Berkshire Section IEEE reserves the right to limit awards to papers that meet the minimum quality standards. Decisions of the IEEE judges are final. Entries become the property of IEEE, Berkshire Section, and may be reprinted at the discretion of IEEE.